

# Dynamical Behaviour of Excitons in ZnSe/GaAs Heterostructures

G.Kudlek, Ch.Fricke, N.Presser, R.Heitz, A.Hoffmann, J.Gutowski\*, and I.Broser  
Institut für Festkörperphysik, Technische Universität Berlin,  
Hardenbergstrasse 36, D-1000 Berlin 12, Germany  
\*Institut für Experimentelle Physik, Universität Bremen, D-2800 Bremen 33

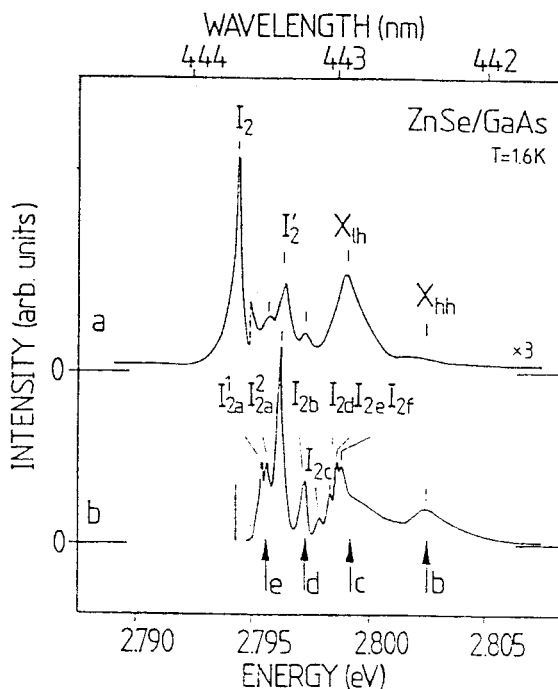
The dynamical behaviour of free and bound excitons in ZnSe/GaAs epilayers grown by molecular beam epitaxy (MBE) was studied in the ps time range. From these investigations we determine the time characteristics of the excitation processes of the donor-bound excitons and the hh-lh conversion time within the free excitons to be 40-60 ps.

## Introduction

Epitaxially grown ZnSe layers are the most promising II-VI compounds for optical and electrooptical devices, like the blue-light-emitting diode<sup>1</sup>. For the realization of ultrafast switching components, the precise knowledge of the dynamical behaviour of excited carriers is necessary. In this paper we investigated for the first time systematically the time dependence of the free- and bound-exciton luminescence in MBE-grown ZnSe/GaAs heterostructures.

## Experimental

The samples were grown on (100) undoped GaAs substrates using a Perkin Elmar model 430 MBE system, see Ref. 2. For the time-resolved measurements we used an actively mode-locked Nd:YAG laser (Coherent) with a frequency-tripling BBO crystal pumping a dye laser.



**Fig. 1**

a) Luminescence spectrum of a 4  $\mu\text{m}$  thick ZnSe/GaAs sample in the excitonic energy range, b) excitation spectrum of the donor-bound-exciton recombination line  $I_2$ . (arrows mark positions of detection of transients, see fig. 3)

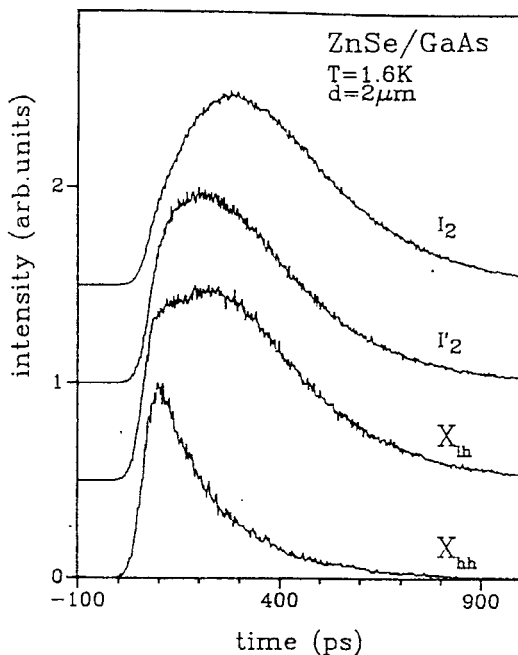
The photoluminescence signal was analyzed by a single-photon-counting system and a micro-channel-plate photomultiplier tube.

### Results and Discussion

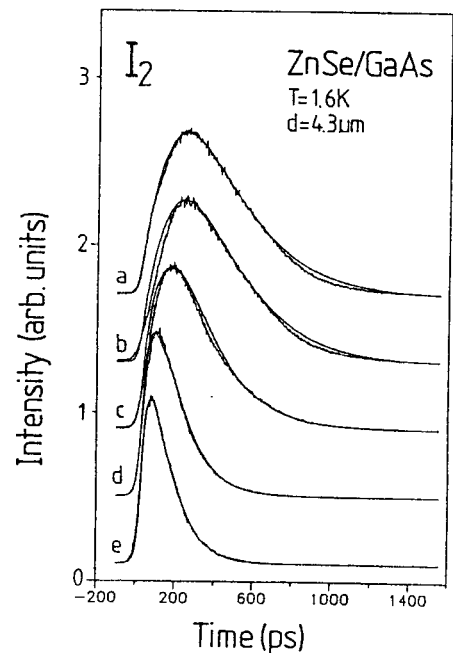
In the time-integrated luminescence (upper part of Figure 1), the strain-split light- and heavy-hole free excitons  $X_{lh}$  and  $X_{hh}$  and two donor-bound exciton transitions  $I_2(lh)$  and  $I_2'(hh)$  are the dominant features. The  $I_1$  line, related to the emission of the acceptor-bound exciton complex, is observed to be rather weak only.

Furthermore, a set of poorly resolved emission lines  $I_{2i}$  could be detected, which are much better resolved in the excitation spectrum of the  $I_2$  (lower part of Figure 1). The  $I_{2i}$  lines were assigned to transitions from or into several excited single-hole states of the  $(D^0, X)$  complex with different quantum numbers  $|n, l\rangle$  (see Ref.3).

In Fig.2, the transients of the free exciton lines  $X_{lh}$  and  $X_{hh}$  and of the donor-bound exciton lines  $I_2$  and  $I_2'$  are shown for the case of nonresonant band-to-band excitation. The rise and lifetimes  $\tau_r$  and  $\tau_d$  of the excitons calculated from the fit of the transients are in the ps time range (see Table 1). For the analysis of  $\tau_r$  and  $\tau_d$  we used a sum of two exponential functions.



**Fig.2**  
Time-dependent transients of the strain-split free excitons  $X_{lh}$  and  $X_{hh}$  and donor-bound-exciton transients  $I_2(lh)$  and  $I_2'(hh)$ .



**Fig.3**  
Transients of the  $I_2$  recombination for different resonant excitation channels (see arrows in fig. 1)

**Table 1** Measured rise times  $\tau_r$  and lifetimes  $\tau_d$  of different excitonic transitions in the case of nonresonant excitation.

Line	$X_{hh}$	$X_{lh}$	$l_2'$	$l_2$	$l_1$
$\tau_r$ (ps)	20	80	110	150	120
$\tau_d$ (ps)	100	150	140	200	300

The observed rise times of the  $l_2'$  and  $l_2$  emissions are correlated with the lifetimes of  $X_{hh}$  and  $X_{lh}$ , respectively. This confirms their assignment to the hh and lh components of the strain-separated ground state of the  $(D^\circ, X)$  complex. The lifetime of the  $X_{lh}$  is significantly longer than this of the  $X_{hh}$  in accordance with their different oscillator strengths.

Additionally, the lifetimes of both free excitons are longer than that of the unsplit free exciton in unstrained bulk ZnSe crystals<sup>4</sup>. This may result from the high purity of the used epilayers.

The rise time of  $X_{hh}$  is considerably shorter than that of  $X_{lh}$ . After nonresonant carrier excitation, formation of free excitons obviously predominantly happens in the hh configuration after which a hh-lh conversion to the  $X_{hh}$  state may occur. The conversion time is 60 ps based on the given data.

To study the influence of strain in different layer regions<sup>5</sup> on the dynamics of the excitation we excited the  $l_2$  line resonantly via the free excitons and several  $l_{2i}$  transitions. The used excitation energies are depicted in Figure 1 as arrows. In Fig. 3, the different  $l_2$  transients are shown. In Table 2, the specific rise and lifetimes are given.

**Table 2** Rise times  $\tau_r$  and decay times  $\tau_d$  of the  $l_2$  luminescence for different excitation situations  
 $E_G$  means nonresonant band-to-band excitation (see spectrum a in Fig. 1)

$l_2$	$E_G$	$E(X_{hh})$	$E(X_{lh})$	$E(l_{2b})$	$E(l_{2a})$
$\tau_r$ (ps)	150	130	90	40	30
$\tau_d$ (ps)	200*	200*	200*	100	80

\* average lifetime of nonexponentially decreasing luminescence

For excitation beyond the band-gap energy  $E_G$  and with the energy of the free excitons  $X_{lh}$  and  $X_{hh}$  the lifetime of the  $l_2$  emission remains constant, while the formation time  $\tau_r$  changes drastically. This could be explained by energy relaxation from the band level to the free excitons and by an additional conversion time from  $X_{hh}$  to  $X_{lh}$ .

Concerning the  $l_2$  decay times  $\tau_d$  it is evident that, first, they considerably shorten when going from nonresonant or free-exciton resonant excitation to resonant excitation via excited  $(D^\circ, X)$  states. Second, it is not possible to fit the transients exactly with only two exponential functions in the case of

nonresonant excitation. This may be explained by the fact that in this case ( $D^{\circ},X$ ) complexes throughout the whole inhomogeneously strained layer are excited and all contribute to the observed decay characteristics. As strain affects the masses of the particles within the complex and, thus, the decay times, the  $I_2$  luminescence is a superposition of components with different time constants<sup>6</sup>.

In the resonant case, ( $D^{\circ},X$ ) complexes in certain layer regions suffering from a specific strain magnitude are selectively excited. Consequently, the  $I_2$  luminescence is no longer a superposition of differently decaying components, and reduced  $\tau_r$  and  $\tau_d$  are observed, corresponding to the real dynamic of the  $I_2$  transition.

**Table 3** *Rise times  $\tau_r$  and lifetimes  $\tau_d$  of the  $I_1$  luminescence for different excitation situations*

$I_1$	$E_G$	$E(X_{hh})$	$E(X_{lh})$
$\tau_r$ (ps)	120	120	70
$\tau_d$ (ps)	300	300	280

Concerning the  $I_1$  luminescence transients, we observed nearly unchanged lifetimes for different excitation conditions, whereas the formation time is strongly depending on the excitation channel (see Table 3). Because  $\tau_d$  is considerably shorter in the case of excitation via  $X_{lh}$  than via  $X_{hh}$ , the  $I_1$  transition could be assigned to a  $lh$  correlated level of the ( $A^{\circ},X$ ) ground state<sup>7</sup>. Generally, a difference of 40-60 ps is detected in the rise times of the  $I_1$  and  $I_2$  when changing the excitation energy from the  $X_{hh}$  exciton to the  $X_{lh}$  exciton transition. This value corresponds well to the difference between the exciton rise times (see Table 1). Therefore, we estimate the conversion between  $hh$  and  $lh$  correlated states to be in the range of 40-60 ps.

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### References

- 1 M.A.Haase, J.Qiu, J.M.DePuydt, and H.Cheng, Appl.Phys.Lett. 59 (1991) 1272
- 2 R.L.Gunshor, and L.A.Kolodziejcki, IEEE J.Quantum Electronics 24 (1988) 174
- 3 G.Kudlek, N.Presser, and J.Gutowski, Semiconductor Science&Technology.6 (1991) A83
- 4 G.Kudlek,U.W.Pohl, Ch.Fricke, R.Heitz, A.Hoffmann, J.Gutowski, and I.Broser, Physica (1992) in press
- 5 G.Kudlek, and J.Gutowski,Journal of Luminescence 52 (1992) 55
- 6 G. Kudlek, thesis, Technische Universität Berlin 1992
- 7 G.Kudlek, N.Presser, and J.Gutowski, Proc.eedings of the 21th ICPS, this issue